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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/827,078	BECK ET AL.	
Examiner	Art Unit	
Akash Saxena	2128	

	SEARCHED		
Class	Subclass	Date	Examiner
703	1-2	6/23/2006	AS
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR)
	DATE	EXMR
INventor Search (Attached)	6/23/2006	AS
EAST Search (attached)	6/23/2006	AS
Google Search (Attached)	6/23/2006	AS
IEEE Sarfch (Attached)	6/23/2006	AS
ACM Search (Attached)	6/23/2006	AS